

Search Notes**Application/Control No.**

10/532,632

Examiner

Emmanuel Bayard

Applicant(s)/Patent under Reexamination

CHEN ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	299	7/10/2007	EB
375	267	7/10/2007	EB
375	150	7/10/2007	EB
375	349	7/10/2007	EB
375	347	7/10/2007	EB
375	295	7/10/2007	EB
375	265	7/10/2007	EB
370	335	7/10/2007	EB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	7/10/2007	EB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
375	295	7/10/2007	EB
375	265	7/10/2007	EB